



Test Textured and Non-Textured Glass

TMS-2000UV-RC

Radial and Circumferential surface measurements with Texture Levels and Ratio reporting

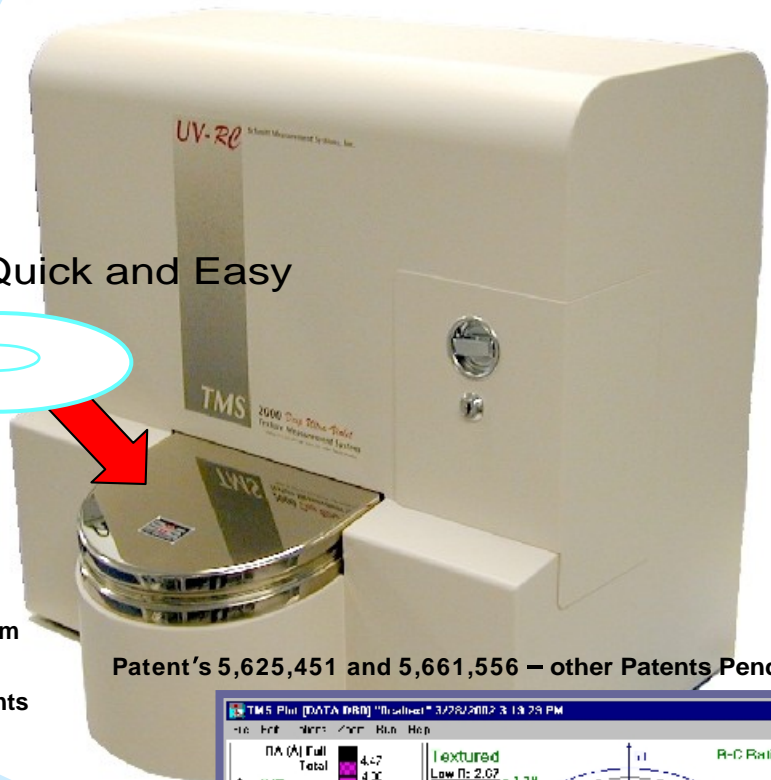
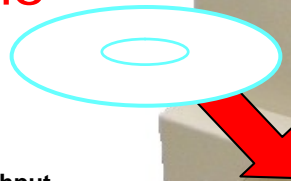
Benefits:

- Quadruple Production Throughput
- Measure Radial, Circumferential
- Unaffected by environmental conditions
- Minimal operator training required
- Lowest cost per measurement of any system
- Stable – Easy to use
- Correlates to other measurement instruments via slope/offset.

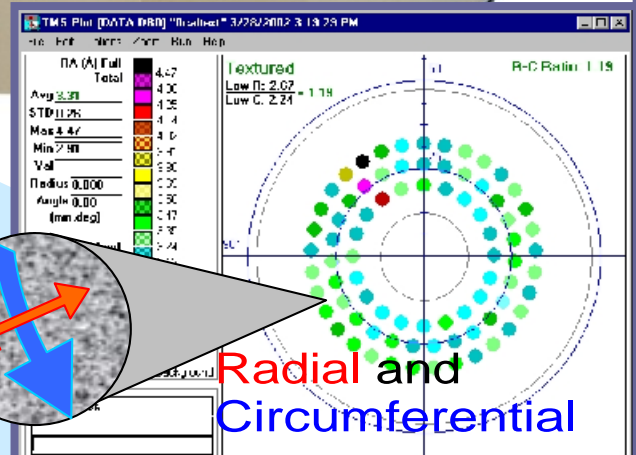
Features:

- Non-Contact Measurements cannot harm test surfaces
- Results – RA, RMS roughness from 1Å up to 500Å
- Cost – Lower costs than Profilometer, AFM or Interferometers
- Precision – Resolution of 0.1Å reproducibility +/-0.35Å and repeatability: +/-0.25 Å
- Speed – Typically 50 test points in 60 sec.

Quick and Easy



Patent's 5,625,451 and 5,661,556 – other Patents Pending



The Ultimate In Microroughness Measurements

The fastest, highest resolution, most stable non-contact microroughness measurement system in the world. Advanced light scatter technology packaged into a system ideally suited for qualifying and quantifying full surface textures and zone microroughness testing. Discover the

ultimate answer to fast, reliable microroughness measurements in glass/ceramic disk manufacturing, with systems that simplify lab to manufacturing correlation. DUV measurements are user configured and correlated via TMS software to known calibration standards.

Technical Specifications

■ Measurements

Source:	DUV Lamp	Repeatability:	$\pm 0.25\text{\AA}$ ★★
Spot Size:	~8mm diameter	Reproducibility:	$\pm 0.35\text{\AA}$ ★★
Number of Spots:	Programmable (full sample to single test point)	Spatial Filtering Frequency:	(wavelength) Low Band: $.122$ to $.41\ \mu\text{m}^{-1}$ (2.41 to 8.20 μm) High Band: $.41$ to $1.43\ \mu\text{m}^{-1}$ (0.70 to 2.41 μm) Full Band: $.122$ to $1.43\ \mu\text{m}^{-1}$ (0.70 to 8.20 μm) Comp Band: Selectable from 0.2 to 150 μm
Primary & Secondary Results:	RA or RMS (Rq) Microroughness P-V, RMS Slope, TIS, Diffuse Reflectance, Total Reflectance, Specular Reflectance		
Speed:	50 Measurements per 60 sec. ★		
Range:	From 1\AA up to 500\AA (RMS or RA)		★ Varies with scan and user setup ★★ Same sample, same machine
Resolution:	0.1\AA		

■ Rotary Stage

Repeatability:	$\pm 0.01^\circ$
Accuracy:	$\pm 0.05^\circ$

■ Linear Stage

Repeatability:	± 0.0005 inch (± 0.01 mm)
Accuracy:	± 0.0010 inch (± 0.03 mm)

■ Operating Environment

41°F (5°C) to 104°F (40°C)

■ Data Generation

ASCII Data Files (Detailed), SPC Data Files, Color plots with Scan Notes,

■ Computer

Pentium class Computer, available with optional

■ Sample Holders

Standard Disks: 65mm, 95mm
Other sizes available

■ Materials

Glass, Glass/Ceramic, Composites

■ Installation

Electrical Requirements: 100-125 VAC – 60Hz
Meets Class ten clean room requirements.

■ Shipping Weights

Computer:	70 lbs / 32 kg
TMS-2000DUV:	90 lbs / 41 kg
Total w/packing	160lbs / 72 kg

■ Dimensions

	Depth:	Width:	Height:
TMS-2000DUV	48.3cm (19")	59cm (23.25")	56.5 (22.25")
Computer:	33cm (13")	17.8cm (7")	38cm (14.96")



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Note: All Specifications are subject to change without notice
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